


<b>Search Notes</b>  	<b>Application/Control No.</b>  10616525	<b>Applicant(s)/Patent Under Reexamination</b>  FUNK ET AL.
	<b>Examiner</b>  Rutten, J. Derek	<b>Art Unit</b>  2192

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
717/127-130; 714/34,35 (Updated text search - see search history printout)	7/6/07	/jdr/
EAST (US-PGPUB; USPAT; EPO; JPO; IBM_TDB; DERWENT - see search history printout)	7/6/07	/jdr/
Tuan Dam, SPE 2192 and Wei Zhen, SPE 2191 (appeal conference)	5/16/08	/jdr/

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner